

L Number	Hits	Search Text	DB	Time stamp
1	652	terminal with external near8 test\$5 same (chip or semiconductor or semi-conductor)	USPAT; US-PGPUB	2004/04/15 12:22
2	365	terminal with external near8 test\$5 near7 (chip or semiconductor or semi-conductor)	USPAT; US-PGPUB	2004/04/15 12:22
3	317	terminal near4 external near8 test\$5 near7 (chip or semiconductor or semi-conductor)	USPAT; US-PGPUB	2004/04/15 12:23
4	32	terminal near4 external near8 test\$5 near7 (chip or semiconductor or semi-conductor) same defect\$5	USPAT; US-PGPUB	2004/04/15 12:24
5	21	terminal near4 external near8 test\$5 near7 (chip or semiconductor or semi-conductor) same defect\$5 same (detect\$4 or determin\$5)	USPAT; US-PGPUB	2004/04/15 12:24
-	1	"6377866"	USPAT; US-PGPUB	2004/04/15 09:54
-	76816	438/\$.ccls.	USPAT; US-PGPUB	2004/04/15 08:08
-	518	438/\$.ccls. and (semiconductor or semi-conductor or chip) same (insept\$4 or detect\$4) same compar\$5	USPAT; US-PGPUB	2004/04/15 08:47
-	681	(438/\$.ccls. or 235/\$.ccls.) and (semiconductor or semi-conductor or chip) same (insept\$4 or detect\$4) same compar\$5	USPAT; US-PGPUB	2004/04/15 08:10
-	13	(438/\$.ccls. or 235/\$.ccls.) and (semiconductor or semi-conductor or chip) same (insept\$4 or detect\$4) same compar\$5 and (ocr or "optical charater recognition")	USPAT; US-PGPUB	2004/04/15 08:13
-	13	(438/\$.ccls. or 235/\$.ccls.) and (semiconductor or semi-conductor or chip) near10 (insept\$4 or detect\$4) near15 compar\$5 same (image ocr or charater or letter\$4)	USPAT; US-PGPUB	2004/04/15 08:16
-	16	(438/\$.ccls. or 235/\$.ccls.) and (semiconductor or semi-conductor or chip) near10 (insept\$4 or detect\$4) same (defect\$4 or fail\$5) same compar\$5 same (image or ocr or charater or letter\$4)	USPAT; US-PGPUB	2004/04/15 08:17
-	1	"6377866" and character	USPAT; US-PGPUB	2004/04/15 08:43
-	0	"6377866" and character and ocr	USPAT; US-PGPUB	2004/04/15 08:43
-	729	438/\$.ccls. and (semiconductor or semi-conductor or chip) same (insept\$4 or detect\$4) same defect\$4	USPAT; US-PGPUB	2004/04/15 08:48
-	122	438/\$.ccls. and (semiconductor or semi-conductor or chip) same (insept\$4 or detect\$4) same defect\$4 same compar\$6	USPAT; US-PGPUB	2004/04/15 08:51
-	71	438/\$.ccls. and (semiconductor or semi-conductor or chip) near15 (insept\$4 or detect\$4) near15 defect\$4 same compar\$6	USPAT; US-PGPUB	2004/04/15 08:51
-	5221	optical near2 character near2 recognition	USPAT; US-PGPUB	2004/04/15 09:54
-	5110	"optical character recognition"	USPAT; US-PGPUB	2004/04/15 09:55
-	456	"optical character recognition" same compar\$4	USPAT; US-PGPUB	2004/04/15 09:55
-	52	"optical character recognition" same compar\$4 same (screen or display\$4)	USPAT; US-PGPUB	2004/04/15 09:56
-	126	("optical character recognition" or ocr) same compar\$4 same (screen or display\$4)	USPAT; US-PGPUB	2004/04/15 10:05
-	25	("optical character recognition" or ocr) same compar\$4 same (screen or display\$4) and (chip or semiconductor or semi-conductor)	USPAT; US-PGPUB	2004/04/15 12:20